


<b>Search Notes</b>  	<b>Application/Control No.</b>  10573646	<b>Applicant(s)/Patent Under Reexamination</b>  MIZUSHIMA ET AL.
	<b>Examiner</b>  DEREK S CHAPEL	<b>Art Unit</b>  2872

SEARCHED			
Class	Subclass	Date	Examiner
359	483, 491, 900 (text only)	12/6/2008	DSC
264	1.1, 1.31, 1.34 (text only)	12/6/2008	DSC

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with Arnel Lavarias about the search	12/5/2008	DSC
Reviewed art of record and previous searches	5/29/2009	DSC
Reviewed art of record	10/16/2009	DSC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

/D. S. C. /  
Examiner, Art Unit 2872